



Gretsi

15ème école d'été de Peyresq
en traitement du signal et des images

Peyresq, du 21 au 27 juin 2020

Physique d'acquisition d'images

Capteurs d'images - Jérôme Vaillant

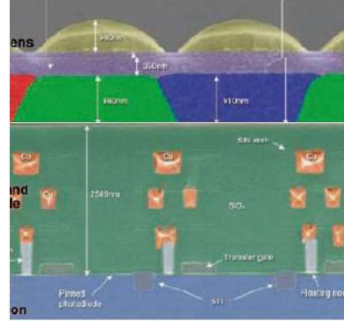
Imagerie non-conventionnelle et co-conception – Corinne Fournier

Agenda



- (Brief) Introduction to image sensors
 - The ubiquitous CMOS image sensor
 - Smartphone camera: a co-design system
- What is a pixel?
 - How does it work
 - Design and fabrication
 - **Optical elements**
 - Implementation in a matrix
 - Noises
- Un-conventional / non-visible pixels
 - Depth sensing with pixels
 - Infrared pixels

Pixel vertical cut view



Optical elements



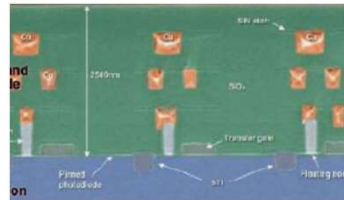
- Microlens



- Color filters



- Optical stack



Optical elements



- Microlens



- Color filters



- Optical stack



21-25 Jun 2021

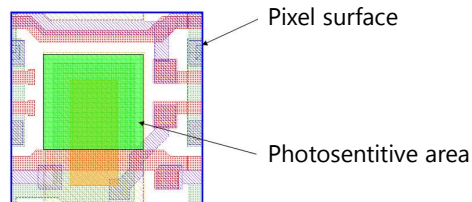
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Microlens



- Primary function: compensate the photodiode fill-factor



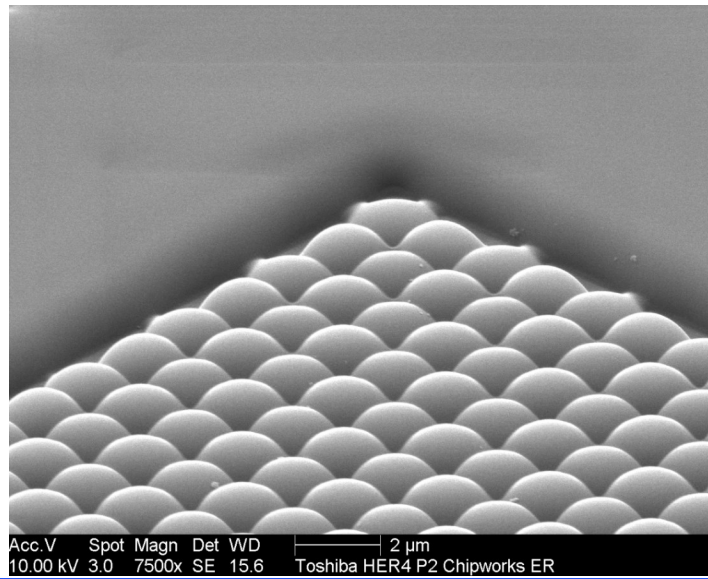
- Secondary functions
 - Spatially sample the image: when on focus, objective image plane = microlens principal plane
 - Reduce the crosstalk between pixels

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MicroLens



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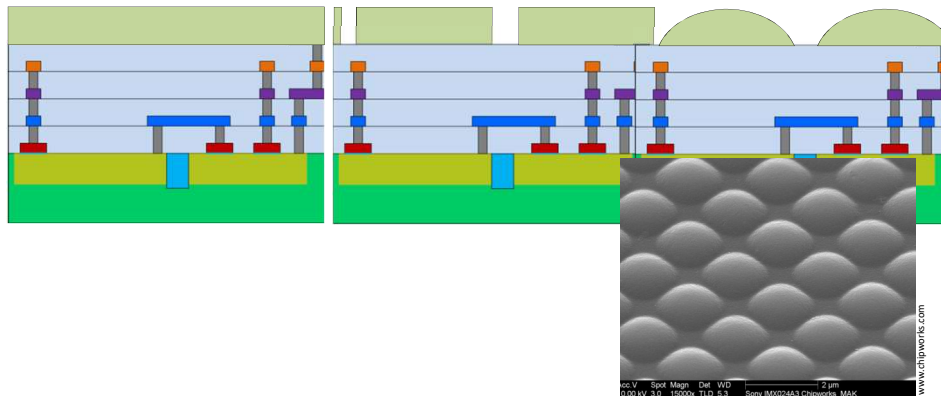
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MicroLens: how to process it?



- Fabrication
 1. Photoresist deposition (spin-coat)
 2. Definition of blocks by photolithography
 3. Formation of convex lens by reflow



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Microlens: where to place it?



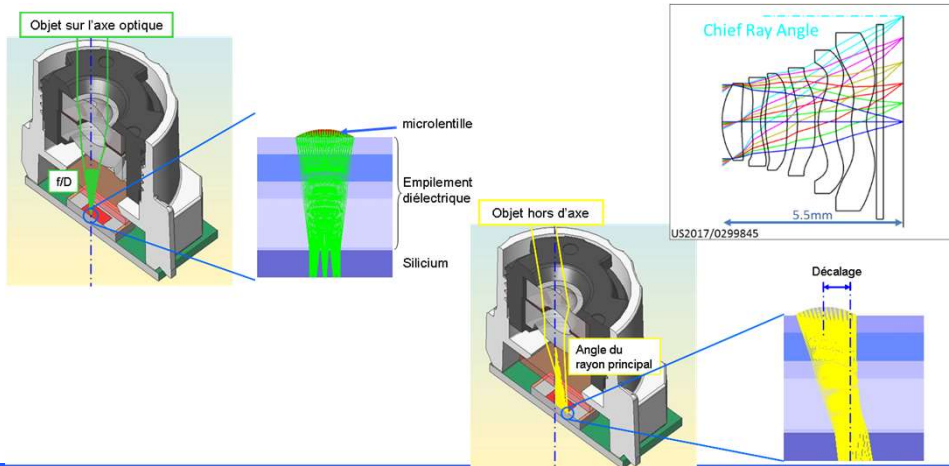
- Obvious placement :
 - Above the photodiode



Microlens: where to place it?

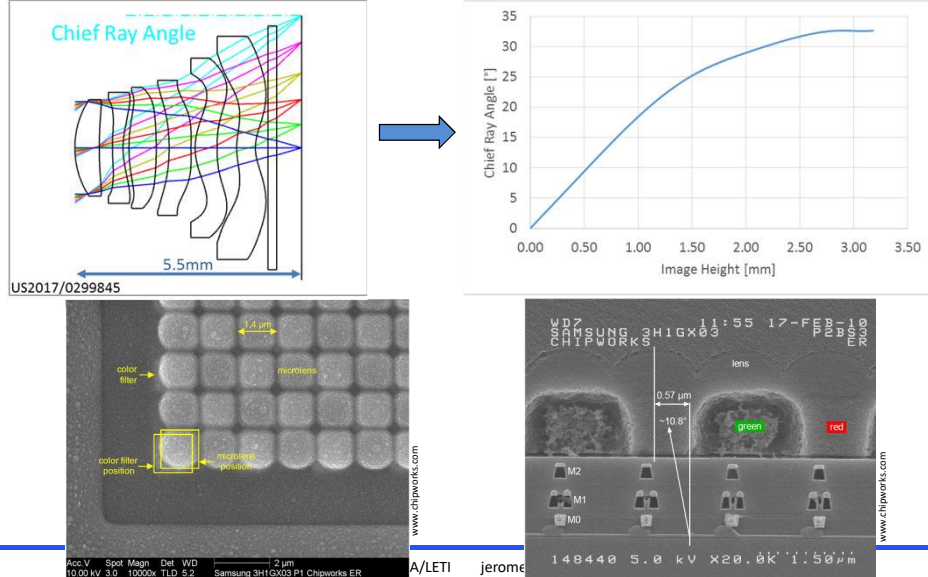


- No so obvious placement:
 - Above the photodiode – OK at the center of the sensor (on axis), but at the edge, Chief Ray Angle (CRA) must be taken into account



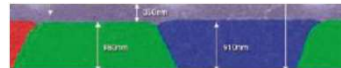
Microlens: where to place it?

- Part of co-design of smartphone camera



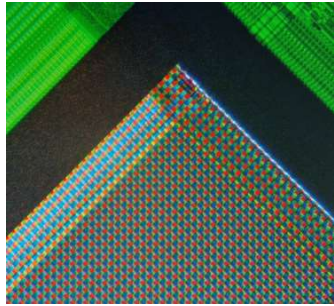
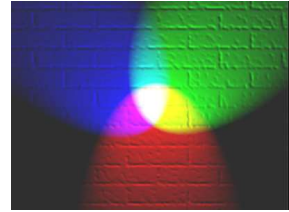
Optical elements

- Microlens
- Color filters
- Optical stack



Color filters

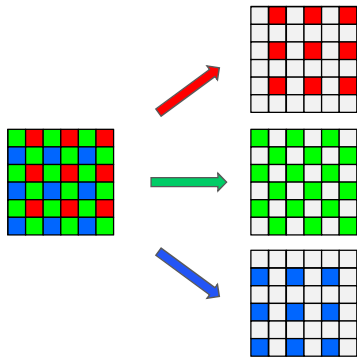
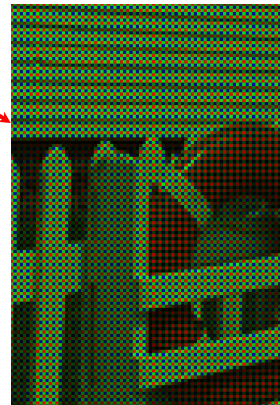
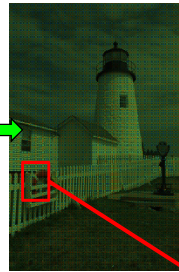
- Primary function: encoding of color seen by human
 - Trichromatic theory: 3 independent colors need to be captured
 - Usually in camera we used Red / Green / Blue color filters
 - Most used pattern: Bayer RGGB (patented in 1974)



- Secondary function (drawback)
 - Image undersampling: 1 color = 1 pixel

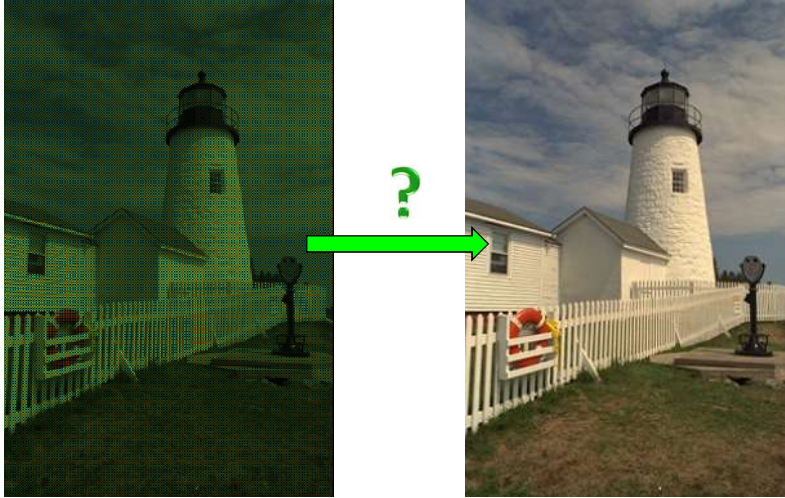
Color filters

- Spatial undersampling:
 - Red $\frac{1}{4}$ undersampling
 - Green $\frac{1}{2}$ undersampling
 - Blue $\frac{1}{4}$ undersampling



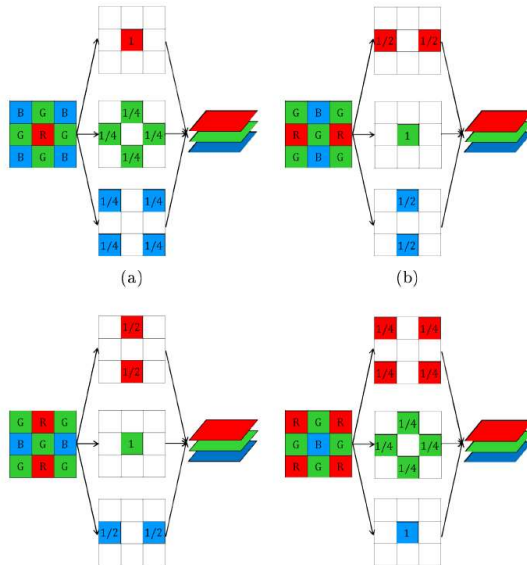
Demosaicing

- Try to recover information



Demosaicing – the traditional approach

- Bilinear interpolation



Demosaicing – the traditional approach



- Artifacts



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Alternative ways for demosaicing



光榮



EUROGRAPHICS 2018 / D. Gutierrez and A. Sheffer (Guest Editors)

Volume 37 (2018), Number 2

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Deep Joint Design of Color Filter Arrays and Demosaicing

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²Instituto Federal Farroupilha – IFFar

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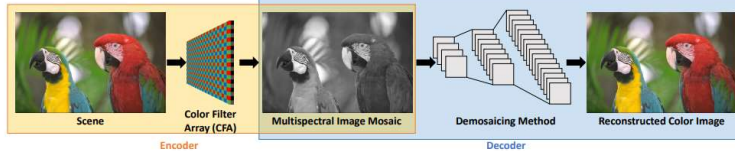


Figure 1: Capture and reconstruction of color images on single-sensor cameras. A color filter array (CFA) selectively allows scene photons with certain wavelengths to reach portions of a monochromatic sensor. A color image is then reconstructed from the filtered samples (multispectral image mosaic) using a demosaicing algorithm. We model this process as an autoencoder: the CFA projection encodes color information onto the monochromatic sensor, which is later decoded by the color-reconstruction method. The joint design of CFA patterns and demosaicing produces high-quality color reconstruction, outperforming existing techniques.

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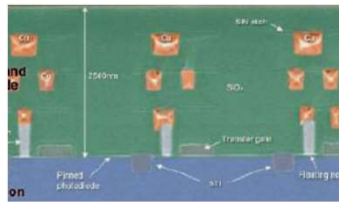
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Optical elements



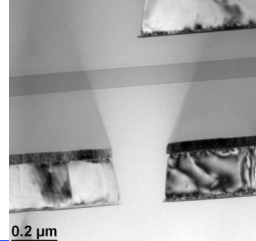
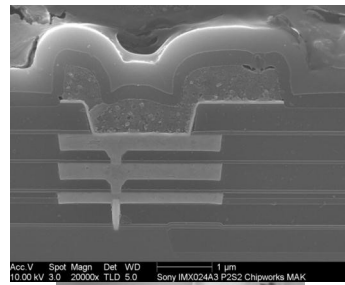
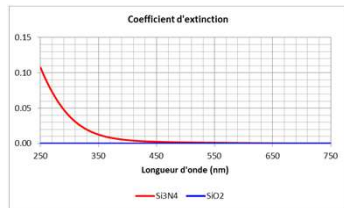
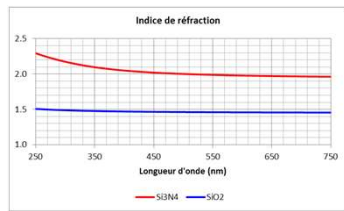
- Microlens
- Color filters
- Optical stack



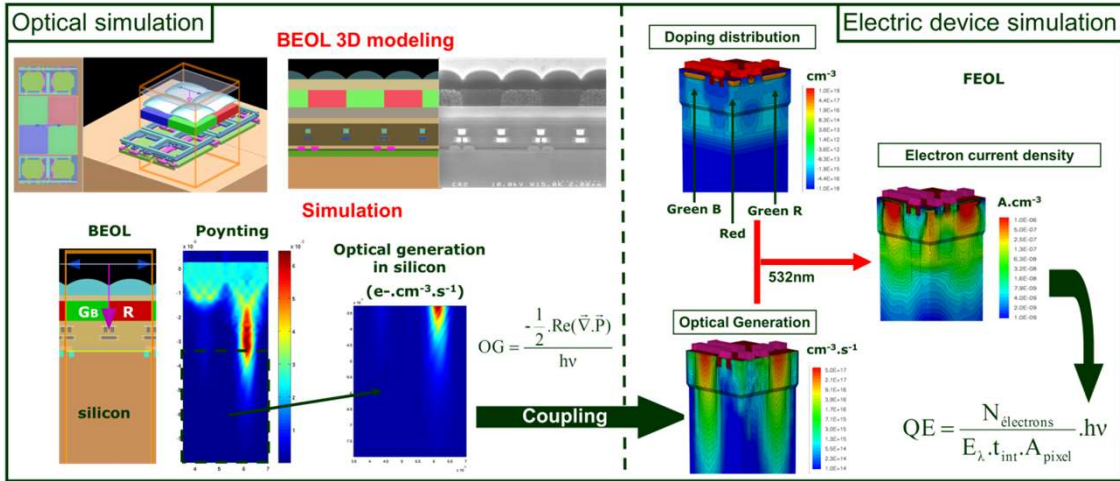
Interconnection stack = Optical stack



- Stack silicon oxide and silicon nitride used to insulate the metallic interconnections



3D opto-electrical simulation of pixel

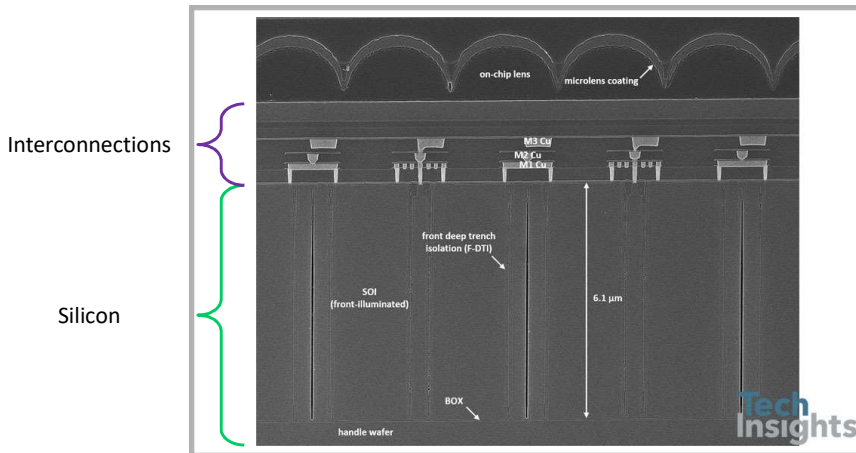


Crocherie et al., From photons to electrons: a complete 3D simulation flow for CMOS image sensor, IISW2009

Frontside illumination (FSI)



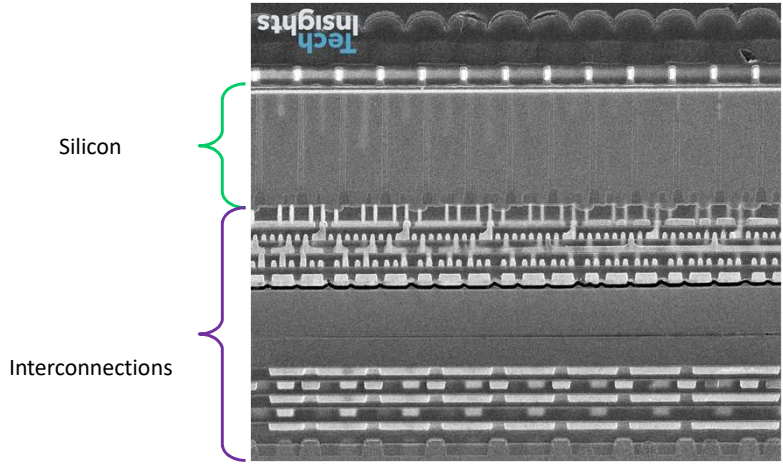
- Standard technology for CMOS integrated circuits
 - Light passes through the interconnection stack



Backside illumination (BSI)



- Wafer is turned over and thinned
 - Light enters the silicon "directly"



FSI vs BSI



FSI		BSI	
Simpler process	Lower native fill-factor	High native fill-factor	More complex process: substrate thinning, mechanical handle, ...
	Lower density for electronic components Management of light path through interconnection	Higher density for electronic components No constraints on interconnection density	
Thick silicon: better for NIR application	Thicker stack between microlens and photodiode	Minimal stack between microlens and photodiode	Thin silicon (typically 3-6µm): lower performance in NIR
	Impact of interconnection layers	Few layers, optimizable for antireflective effect	

Agenda

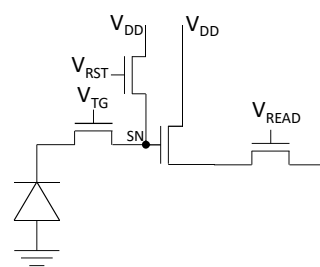


- (Brief) Introduction to image sensors
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Implementation in a matrix



- Row signals
 - V_{RST} , V_{READ} , V_{TG}
- Column signal
 - V_{OUT}



Two main architectures



- Two types of sensor depending on their integration strategy
 - Rolling Shutter
 - Global Shutter

Two main architectures



- Two types of sensor depending on their integration strategy
 - **Rolling Shutter**
 - Global Shutter

Rolling shutter



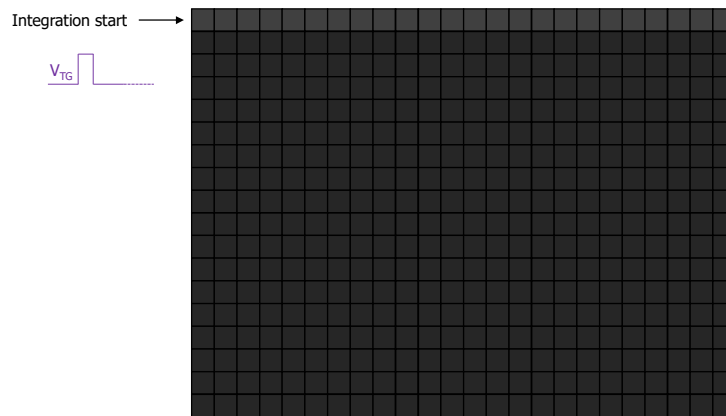
- Command signals send through a shift register line by line



Rolling shutter



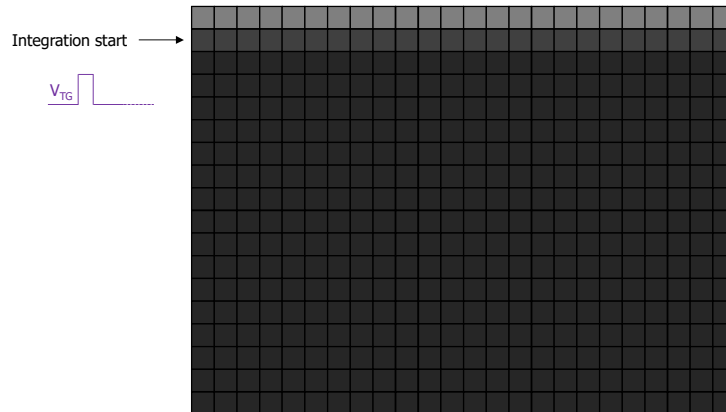
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Rolling shutter



- Command signals send through a shift register line by line



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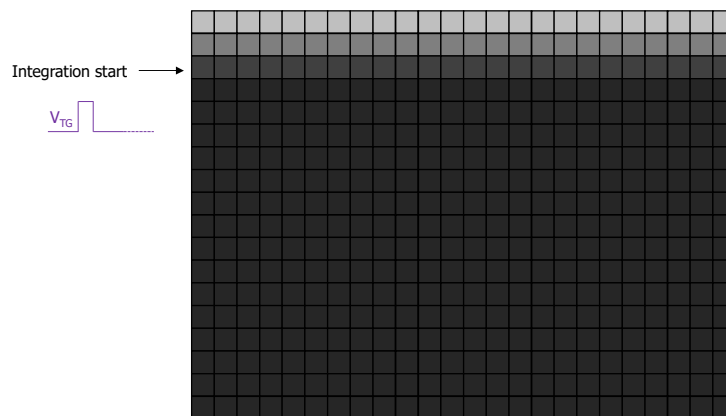
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Rolling shutter



- Command signals send through a shift register line by line



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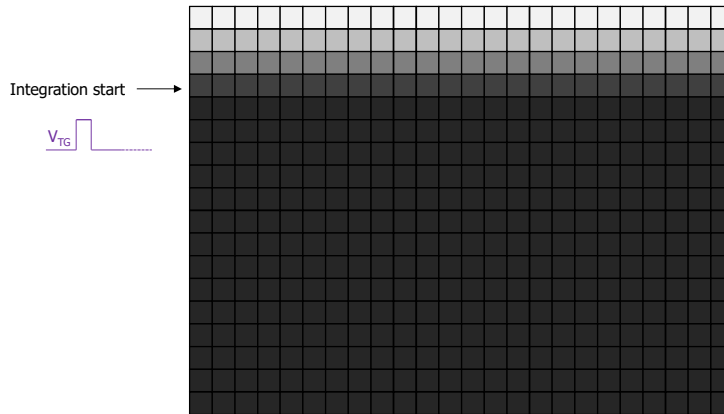
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Rolling shutter



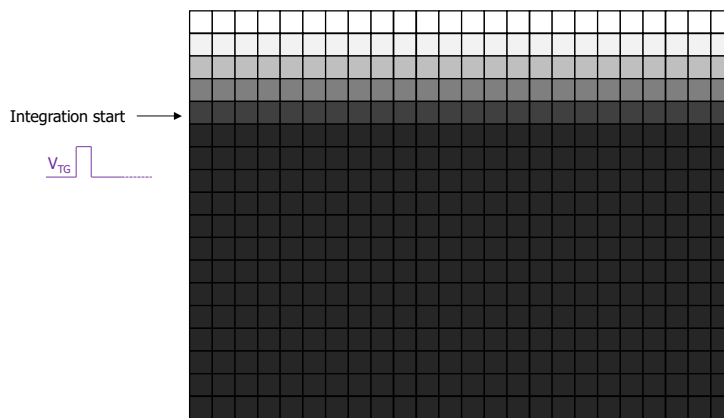
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Rolling shutter



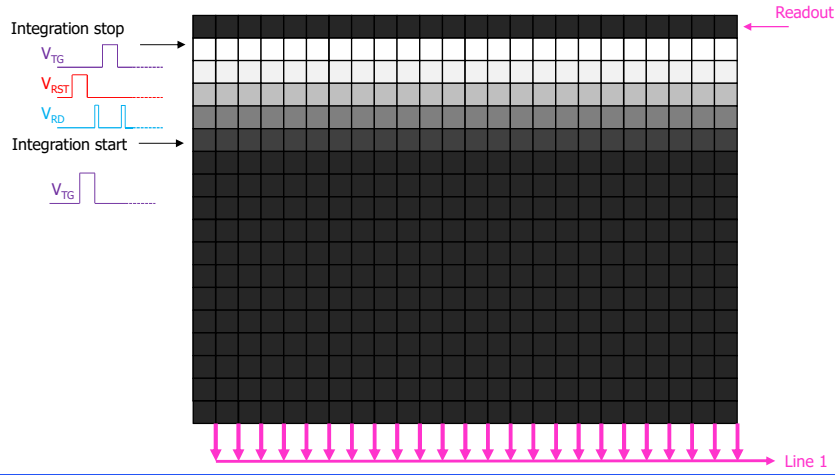
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Rolling shutter



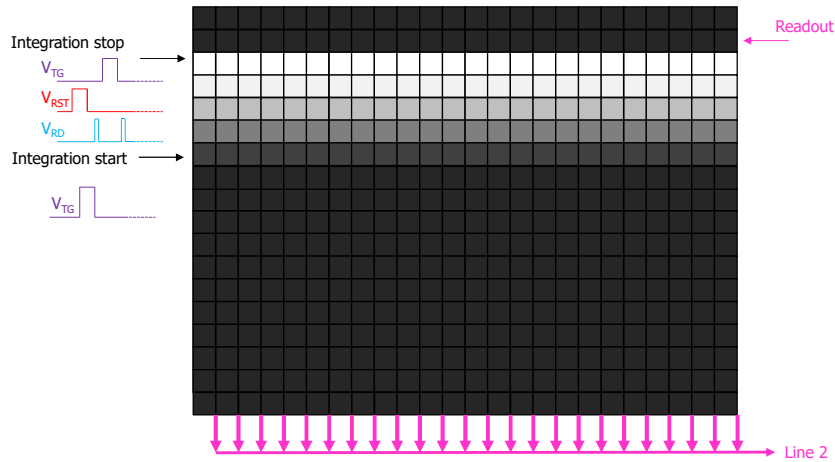
- Command signals send through a shift register line by line



Rolling shutter



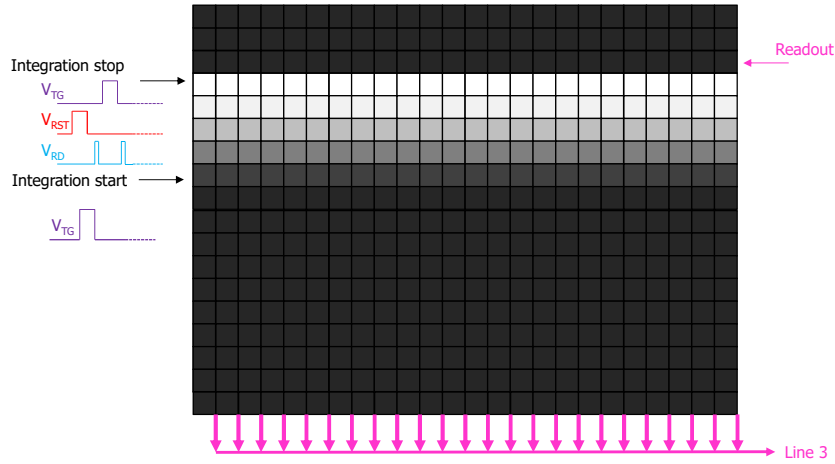
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Rolling shutter



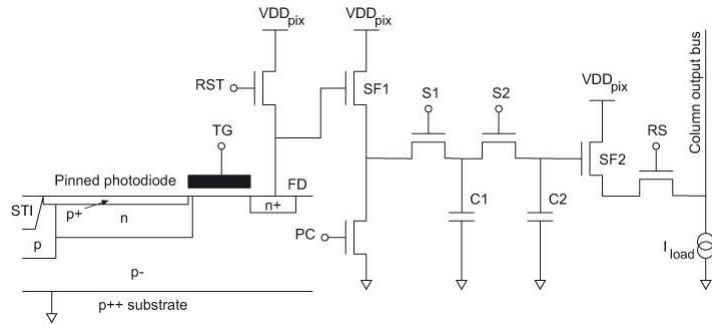
- Command signals send through a shift register line by line



Two main architectures



- Two types of sensor depending on their integration strategy
 - Rolling Shutter
 - **Global Shutter**
 - More complex design: lower fill factor / larger pixel



Global shutter



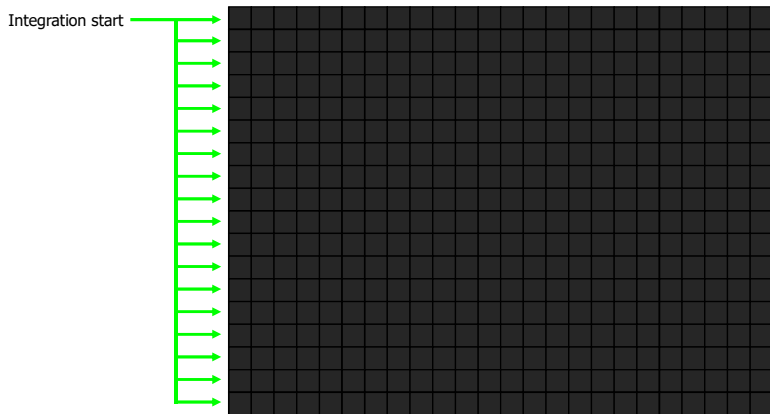
- Integration start / stop send to all pixels at a time



Global shutter



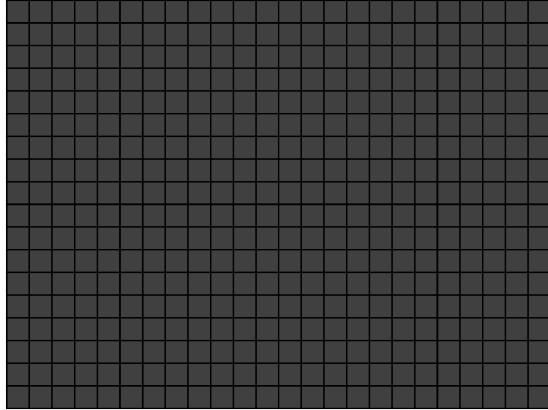
- Integration start / stop send to all pixels at a time



Global shutter



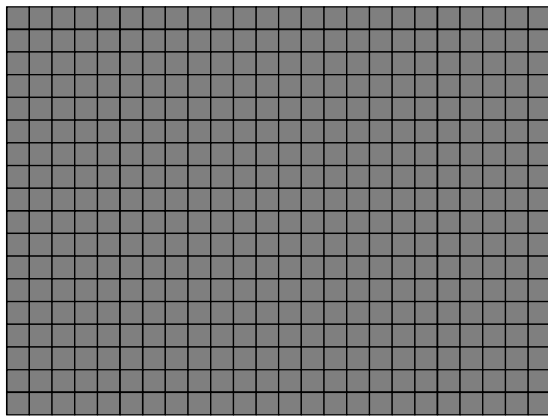
- Integration start / stop send to all pixels at a time



Global shutter



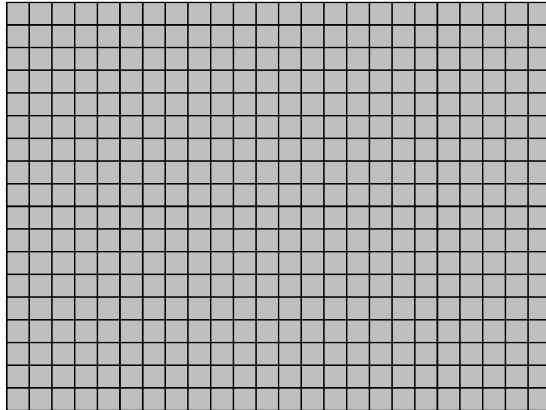
- Integration start / stop send to all pixels at a time



Global shutter



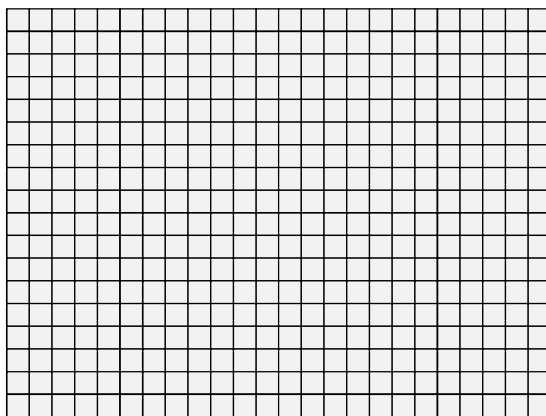
- Integration start / stop send to all pixels at a time



Global shutter



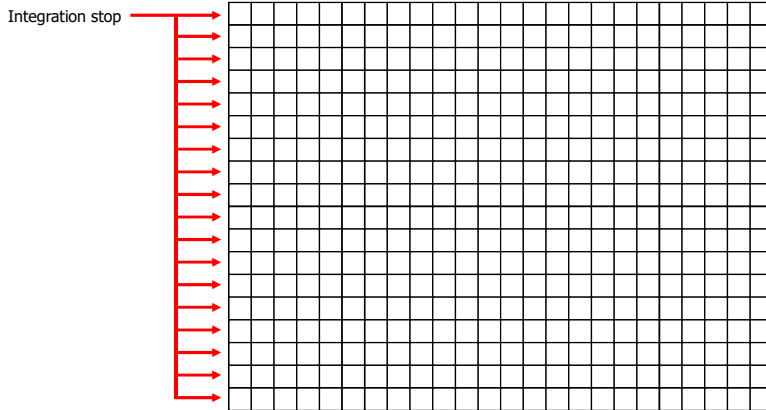
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Global shutter



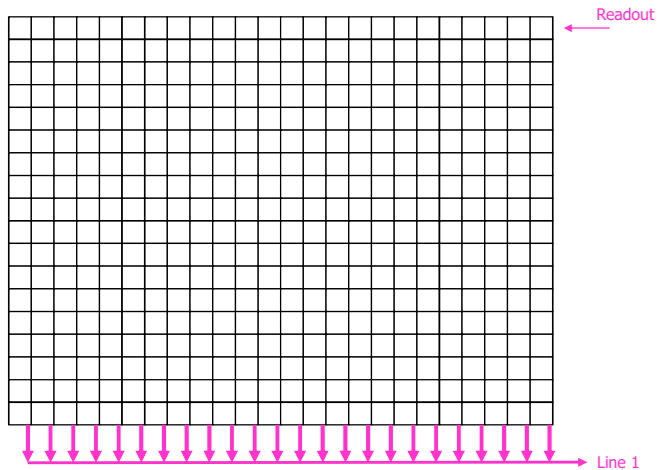
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Global shutter



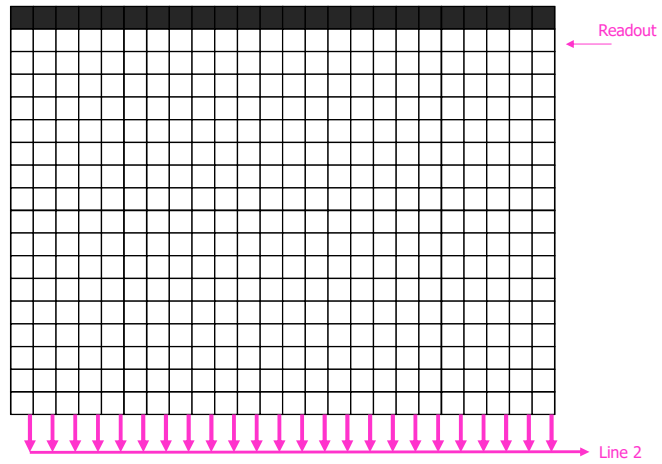
- Then, readout is done line by line via the shift register (i.e. in a rolling mode)



Global shutter



- Then, readout is done line by line via the shift register (i.e. in a rolling mode)



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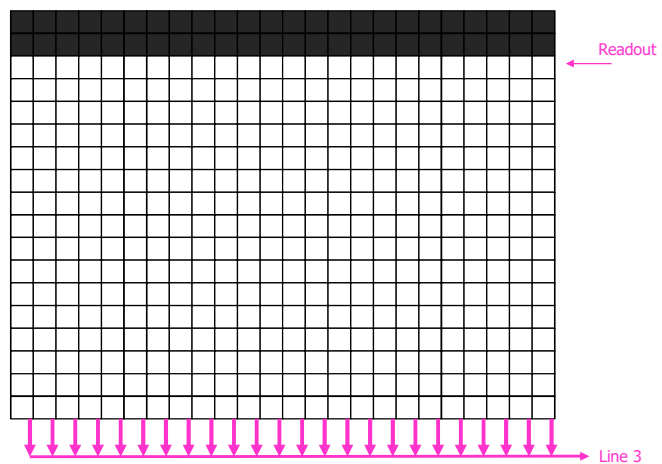
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Global shutter



- Then, readout is done line by line via the shift register (i.e. in a rolling mode)



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Two main architectures



- Two family of sensor depending on their integration strategy
 - Rolling Shutter
 - **Global Shutter**
 - More complex design: lower fill factor / larger pixel



Rolling vs Global shutter



Rolling Shutter		Global Shutter	
Small pixel	Rolling shutter effect	No rolling shutter effect "Freeze the scene"	Larger pixel
Charge domain (4T pixels) No reset noise			Voltage domain used to reduce pixel pitch, but at the cost of reset noise
			Impact of light during readout time (Parasitic Light Sensitivity, PLS)

Agenda

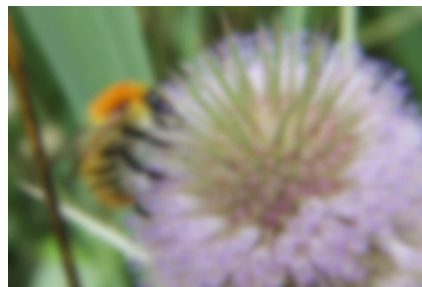
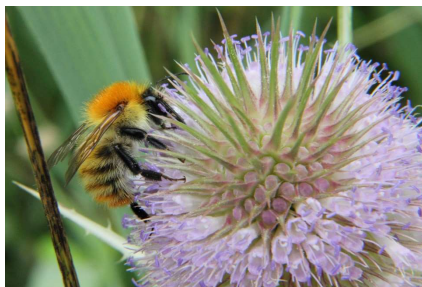


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Noises / Performances



- Performances \leftrightarrow SNR
 - What we define as signal?
 - Noise?



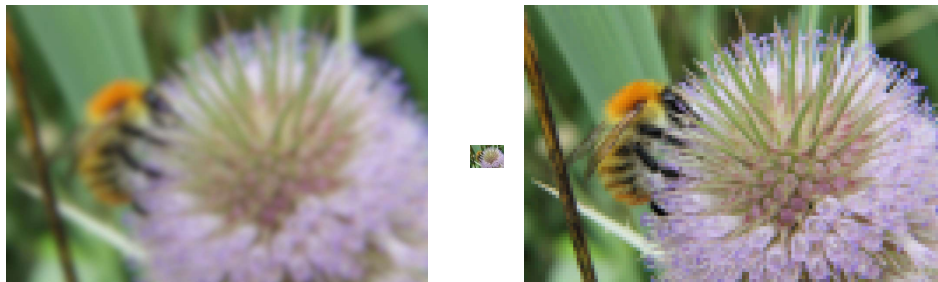
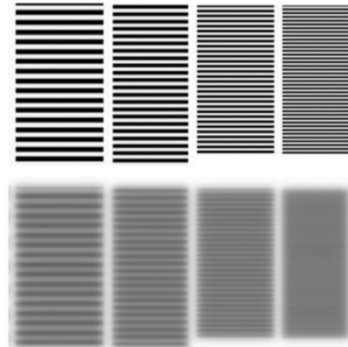
Spatial resolution



Spatial resolution



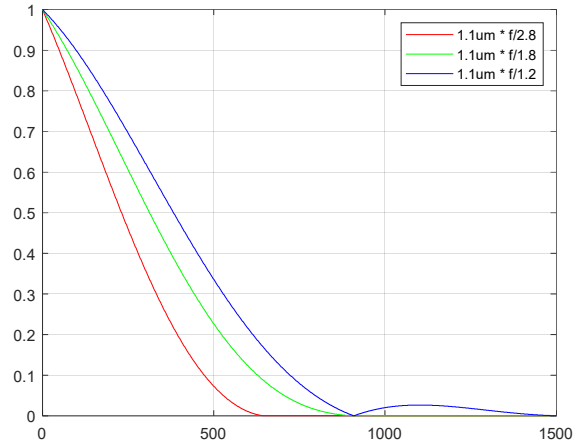
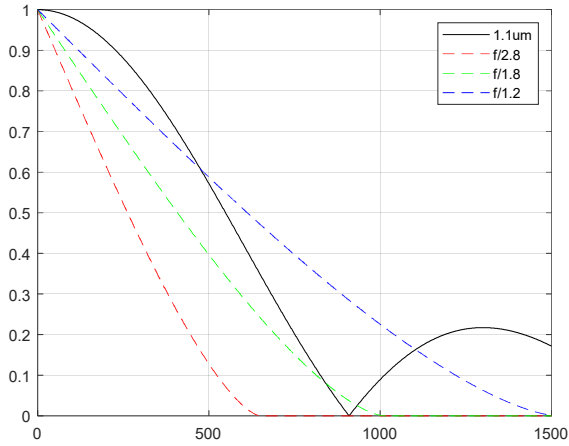
- Resolution \neq definition
 - Resolution: ability to record spatial frequency
 - Definition: number of pixels in the image



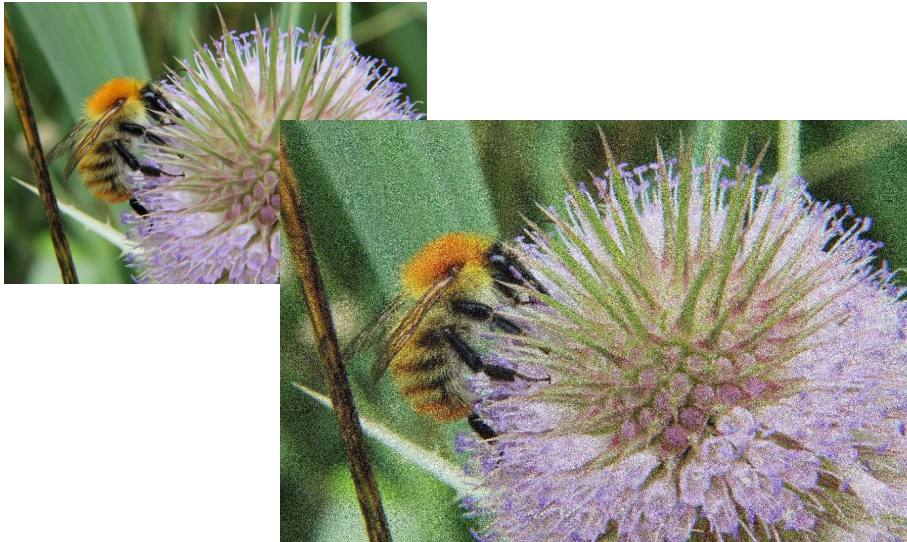
Spatial resolution



- Pixel MTF & objective MTF



Spatial noise



Noise



- Photon shot noise
- Reset noise
- Dark current
- Readout noise
- Spatial non-uniformities

Photon shot-noise

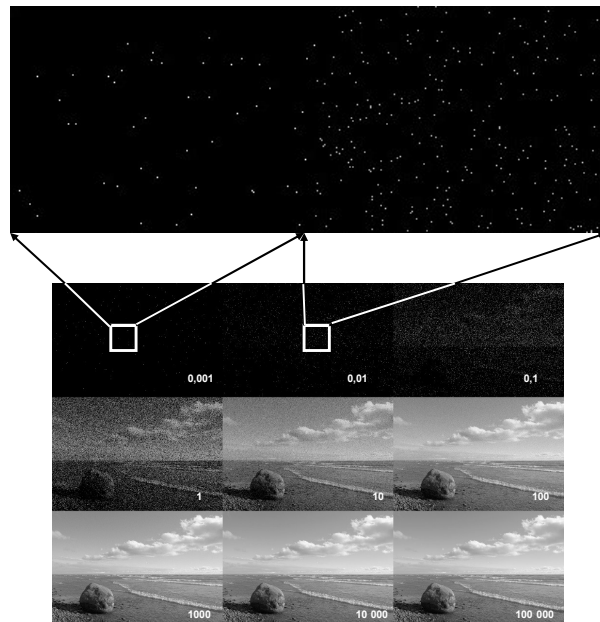


- Due to particle nature of light
- Statistics of photon arrival – Poisson distribution:

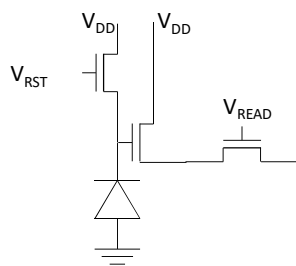
$$P(X_\lambda = k) = \frac{\lambda^k e^{-\lambda}}{k!}$$

$$E(X) = \lambda \text{ and } Var(X) = \lambda$$

$$SNR = \frac{E(X)}{\sqrt{Var(X)}} = \frac{\lambda}{\sqrt{\lambda}} = \sqrt{\lambda}$$



Reset noise

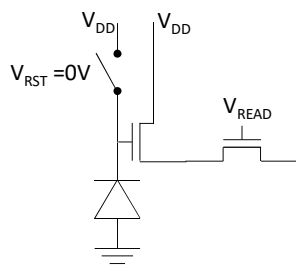


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Reset noise

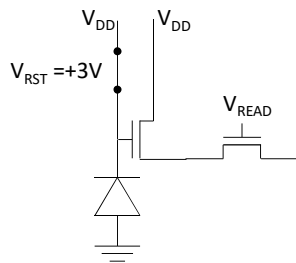


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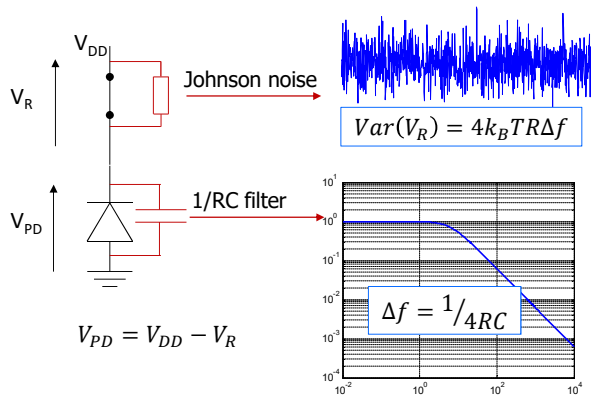
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Reset noise



Reset noise

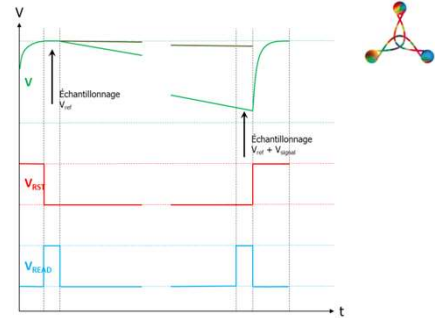


$$\sigma_{V_{PD}}^2 = \frac{k_B T}{C}$$

Reset noise

- On 3T pixel:

- Two uncorrelated sampling $\sigma_{e^-} = \frac{C}{q} \sqrt{\frac{2k_B T}{C}} = \frac{1}{q} \sqrt{2k_B T C} \text{ [e}^-\text{]}$
- Ambiant Temp.: 300K
- Pixel $2\mu\text{m} \Rightarrow C_{\text{pix}} \approx 10\text{fF}$ $\sigma_{e^-} \approx 60 e^-$
- $k_B = 1,38 \times 10^{-23} \text{ J.K}^{-1}$



Number of photons per pixel

- Main objective with $f/D=16$ and a transmission of $T=90\%$
- Macro photography, $\gamma = -1$
- Maximum sunlight illumination: $E_s = 10\,000 \text{ lux}$
- Average reflectivity of the scene $R=18\%$
- Pixel pitch $2\mu\text{m}$
- Integration time $1/100\text{s}$



$$E_p = \frac{RT}{4(f/D)^2 \times (\gamma-1)^2} E_s \approx 0.40 \text{ lux}$$

$$N_{\text{photons}} = E_p \times p_{\text{pixel}}^2 \times \tau_{\text{int}} \approx 160 \text{ photons/pixel}$$

20 Feb 2019

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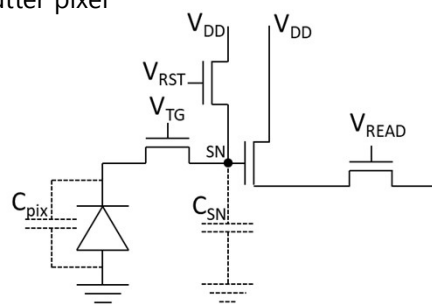
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Reset noise

- Can be cancelled by doing Correlated Double Sampling (CDS)
 - Done inside the pixel for 4T architecture
 - Current standard architecture for CMOS rolling shutter pixel

- In datasheet:

- Charge domain => no reset noise
- Voltage domain => reset noise

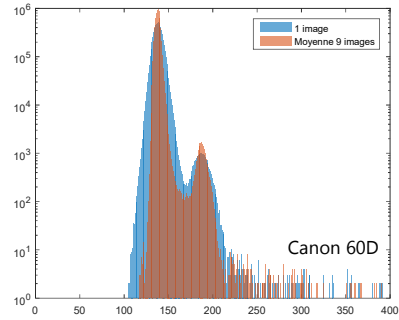


TG : Transfer Gate
SN : Sense Node

Dark current



- Collected e^- even without illumination
 - Trap assisted thermal generation at interfaces Si/SiO₂ (and in Si volume)
- Properties:
 - Strongly temperature dependent $\times 2$ every $\Delta T \approx 8^\circ C$
 - Can be managed by interfaces passivation.
 - Distribution over the matrix: main Gaussian distribution + secondary population + outlier
 - A given pixel follows a Poisson statistic
- Mean value (over the matrix)
 - I_{dark} down to $\sim 0.1 e^-/s$ @ $25^\circ C$ in $1\mu m$ and below pixels
- Spatial variation over the matrix
 - DSNU: Dark Signal Non-Uniformity
- Can be partially corrected by dark image subtraction
 - Poisson noise remains

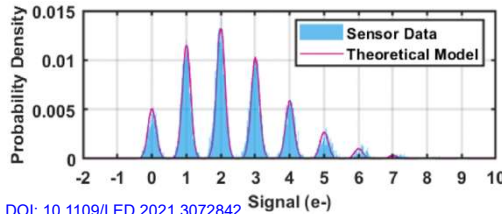


Read noise

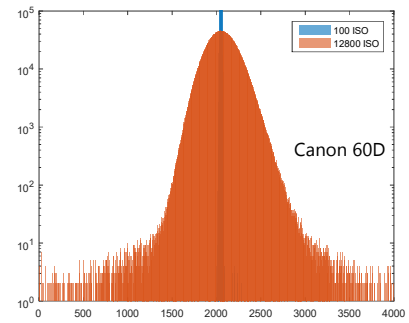


- Sum of all electronic noises between photodiode and output
 - 1/f noise
 - Traps in transistor channel
 - Reset noise of sampling capacitances
 - Reset noise in case of 3T pixel
 - Gaussian statistic is a reasonable assumption
- Typical value on small pixels: $\sigma_{read} \approx 1.5 - 3 e^-$
 - Low noise sensors recently developed (gigajot.tech)

$$\sigma_{read} = 0.19 e^-$$

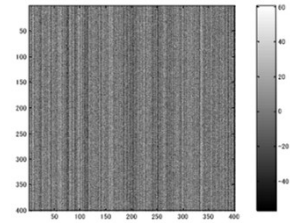


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Fix Noises

- Fixed Pattern Noise (FPN)
 - Mismatch of transistor parameters
 - At pixel level (spatial high frequency)
 - In readout circuit at the bottom of the column \Rightarrow vertical pattern
 - Could be partially corrected by dark image subtraction
- Photon Response Non-Uniformity
 - Spatial variation of pixel sensitivity
 - Could be corrected by taking a flat field image



Quantification noise

- Due to finite number of digital levels (# of ADC bits)

$$\sigma_{quant}^2 = \frac{LSB^2}{12}$$



3 x 8bits

3 x 6bits

3 x 4bits



3 x 2bits



3 x 1bits



Dynamic



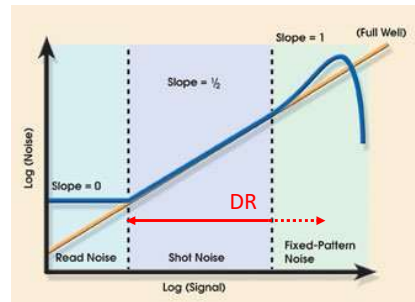
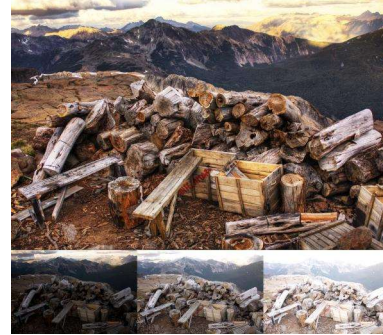
Dynamic Range



- Range of signal that can be captured in one single frame

- $DR \neq SNR$ $DR = 20 \times \log\left(\frac{Saturation}{noise\ floor}\right)$ [dB]

- SNR_{max} achieved at saturation
 - Limited by photon shot-noise $SNR_{max} = \sqrt{Q_{sat}}$
- $SNR_{min} = 1$ is noise floor



<https://www.photonics.com/Article.aspx?AID=15891>